

12th Pacific Northwest Test Workshop

aka: BAST 2003

Santa Rosa, California, Feb 25 - 28, 2003

CALL FOR PARTICIPATION

Committee:

General Chair:

Edward J. McCluskey, Stanford

Co-General Chair:

Subhasish Mitra, Intel

Program Chair:

Samy Makar, Transmeta

Registration Chair:

Ahmad Alyamani, Stanford

Local Arrangements:

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Mike Purtell, Advantest

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Edward J. McCluskey, Stanford

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Program Committee:

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Frank Bouwman, Philips

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The 12th annual BAST workshop, co-sponsored by the Stanford University Center for Reliable Computing (CRC) and the IEEE Computer Society Test Technology Technical Council (TTTC)*, will be held February 25 - 28, 2003, in Santa Rosa, California. BAST is an informal workshop whose objective is to bring together engineers from the Pacific Northwest to discuss current work on testing electronic circuits.

Attendance at BAST is restricted to fewer than 50 persons in order to facilitate better sharing of ideas. This workshop is unique in that all attendees are on the program; everyone attending is expected to stay at the workshop for its duration, and to participate. Interaction is encouraged during every presentation, and during breaks and social events. Programs and reports from previous BAST workshops are available from the web site listed at the bottom of this page.

Interested persons are invited to submit a proposal containing a brief abstract of what they would like to present. Possible suggestions include:

System on Chip Test Methodology
Impact of Deep Sub-micron Test on ATE
Design for Debug and Testability
Fault Coverage and Fault Models
Test Research
Online Test

Mixed Signal Testing
Verification
Embedded Memory Test
Future Test Issues
Testing High Speed Designs

This is not an exclusive list; all interesting abstracts related to test are invited for submission (see reverse side for application information). If you are interested in attending, please email a softcopy of your proposal immediately to:

Ahmad Alyamani

E-mail: alyamani@crc.stanford.edu

Gates Bldg. 2A, Room 234

Voice: 650-725-0487

Stanford, CA 94305

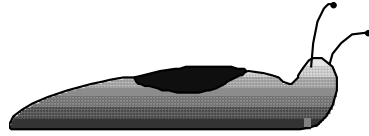
FAX: 650-723-1451

Applications to attend the workshop will be considered on a first come first serve basis. Your proposal submission will reserve you a place and is not considered a commitment. **Invitations will be mailed out promptly upon receipt of your proposal.** There is no on-site registration.

BAST web site: <http://crc.stanford.edu/BAST/BAST.html>

*Approval Pending

(See Reverse Side)



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Proposal for Participation, Please turn in immediately.

Name: _____

Address: _____

Tel.: () _____ Fax: () _____

E-Mail: _____

Company or University: _____

ATTENDEE INFORMATION

Test Interests/experience	Title of Discussion	Previous BAST attendance
Abstract of your discussion: (Please be brief)		

(See Reverse Side)